

N-Channel Enhancement Mode Power MOSFET

General Description

The series of Power MOSFETs use advanced technology and design. This high voltage MOSFET fits Switched applications.

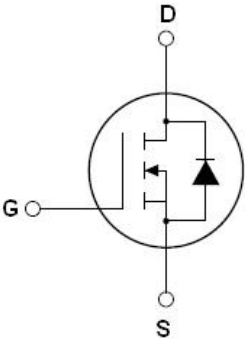
Features

- High speed switching
- Intrinsic capacitances and Qg minimized
- 100% Avalanche Tested

Application

- Switched applications

$V_{DS\ min@T_{jmax}}$	1650	V
$R_{DS(ON)TYP}$	5.5	Ω
I_D	3	A
Q_g	32	nC



Schematic diagram

Package Marking And Ordering Information

Device	Device Package	Marking
NCE3N150D	TO-263	NCE3N150D



TO-263

Table 1. Absolute Maximum Ratings ($T_c=25^{\circ}C$)

Parameter	Symbol	NCE3N150D	Unit
Drain-Source Voltage ($V_{GS}=0V$)	V_{DS}	1500	V
Gate-Source Voltage ($V_{DS}=0V$) DC	V_{GS}	± 30	V
Continuous Drain Current at $T_c=25^{\circ}C$	$I_{D(DC)}$	3	A
Continuous Drain Current at $T_c=100^{\circ}C$	$I_{D(DC)}$	2.1	A
Pulsed drain current (Note 1)	$I_{DM(pluse)}$	9	A
Maximum Power Dissipation($T_c=25^{\circ}C$)	P_D	187	W
Derate above $25^{\circ}C$		1.24	W/ $^{\circ}C$
Single pulse avalanche energy (Note 2)	E_{AS}	225	mJ
Single pulse avalanche current (Note 2)	I_{AS}	3	A
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55...+175	$^{\circ}C$

* limited by maximum junction temperature

Table 2. Thermal Characteristic

Parameter	Symbol	NCE3N150D	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R_{thJC}	0.8	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient (Maximum)	R_{thJA}	50	$^{\circ}\text{C}/\text{W}$

Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
On/off states						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =1mA	1500			V
Zero Gate Voltage Drain Current(Tc=25℃)	I _{DSS}	V _{DS} =1500V, V _{GS} =0V			1	μA
Zero Gate Voltage Drain Current(Tc=125℃)	I _{DSS}	V _{DS} =1500V, V _{GS} =0V			100	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±30V, V _{DS} =0V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	3	4	5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =1.5A		5.5	7.5	Ω
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =40V, V _{GS} =0V, F=1.0MHz		1700		pF
Output Capacitance	C _{oss}			61		pF
Reverse Transfer Capacitance	C _{rss}			5.5		pF
Total Gate Charge	Q _g	V _{DS} =1200V, I _D =1.5A, V _{GS} =10V		32		nC
Gate-Source Charge	Q _{gs}			8.7		nC
Gate-Drain Charge	Q _{gd}			12		nC
Intrinsic gate resistance	R _G	f = 1 MHz open drain		2		Ω
Switching times						
Turn-on Delay Time	t _{d(on)}	V _{DD} =750V, I _D =1.5A, R _G =3Ω, V _{GS} =10V		22		nS
Turn-on Rise Time	t _r			45		nS
Turn-Off Delay Time	t _{d(off)}			42		nS
Turn-Off Fall Time	t _f			58		nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}	T _C =25℃			3	A
Pulsed Source-drain current(Body Diode)	I _{SDM}				9	A
Forward On Voltage	V _{SD}	T _j =25℃, I _{SD} =3A, V _{GS} =0V		0.8	1.1	V
Reverse Recovery Time	t _{rr}	T _j =25℃, I _F =3A, di/dt=100A/μs		390		nS
Reverse Recovery Charge	Q _{rr}			2.2		uC
Peak Reverse Recovery Current	I _{rrm}			11		A

Notes 1.Repetitive Rating: Pulse width limited by maximum junction temperature

2. $T_J=25^{\circ}\text{C}, V_{DD}=50V, V_G=10V, R_G=25\Omega$

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

Figure1. Safe operating area

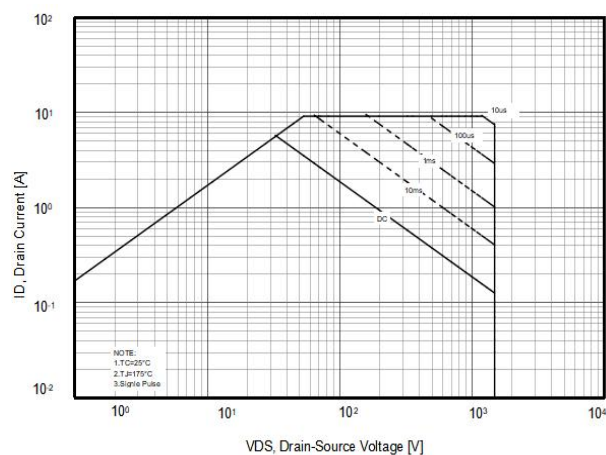


Figure2. Source-Drain Diode Forward Voltage

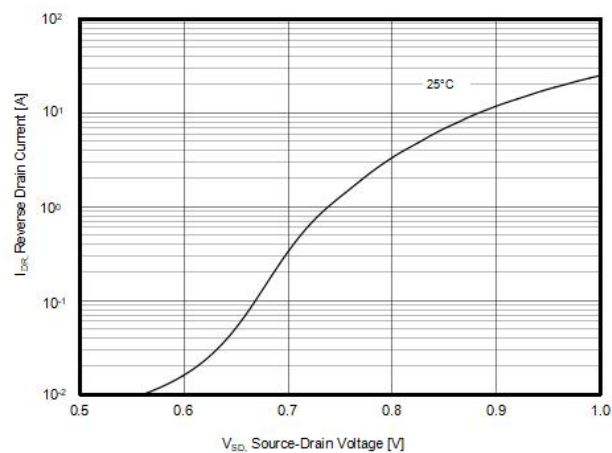


Figure3. $R_{DS(ON)}$ vs Junction Temperature

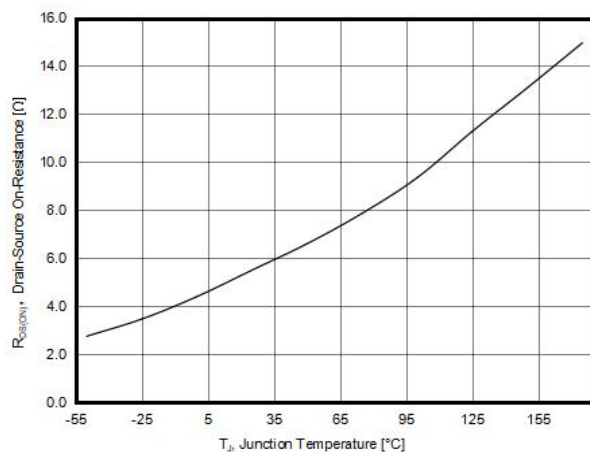


Figure4. BV_{DSS} vs Junction Temperature

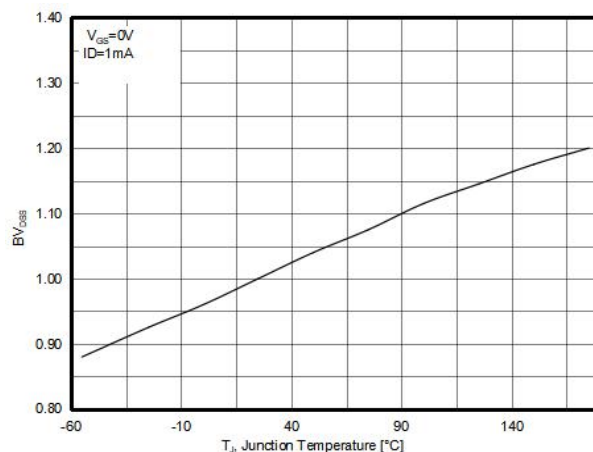


Figure5. Maximum I_D vs Junction Temperature

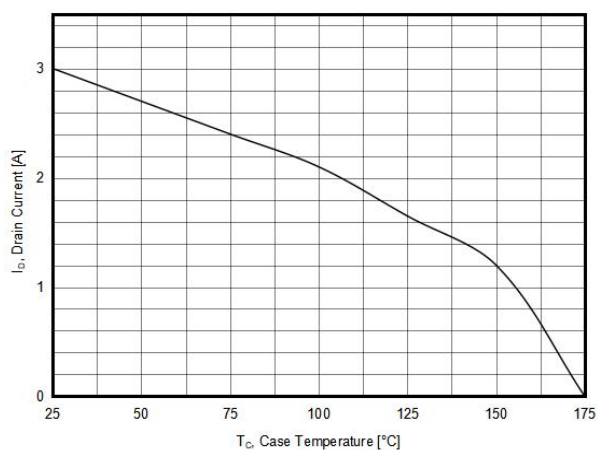


Figure6. Output characteristics

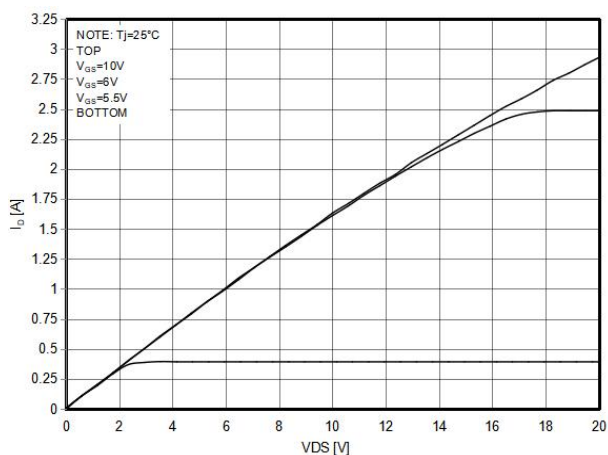


Figure7. Capacitance

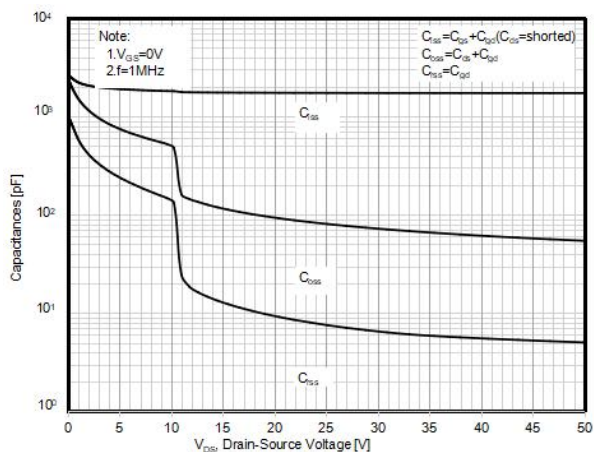


Figure8. Transfer characteristics

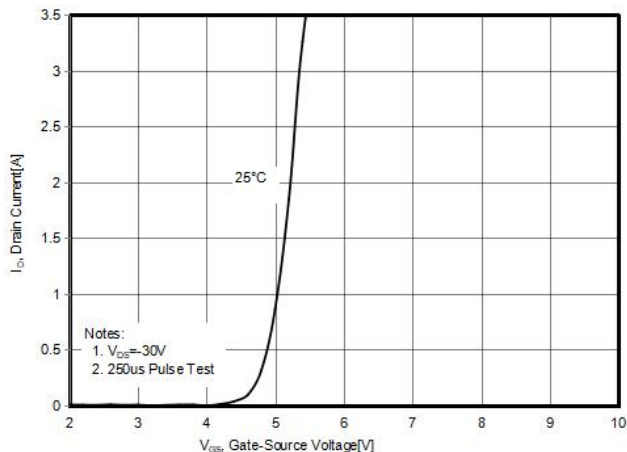


Figure9. Static drain-source on resistance

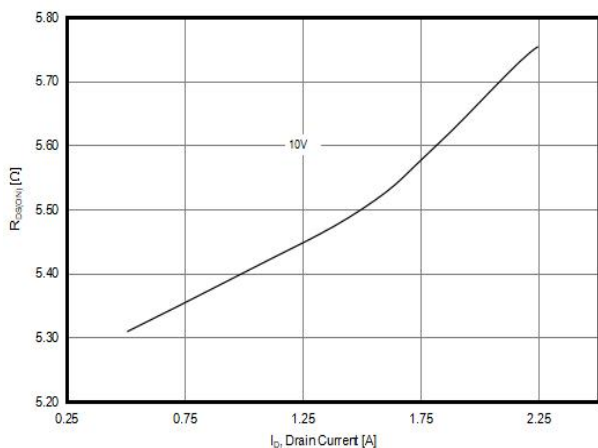
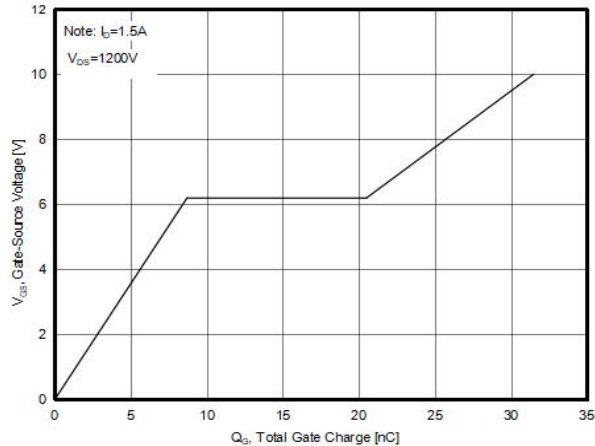
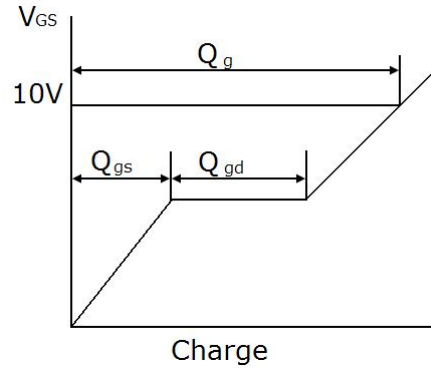
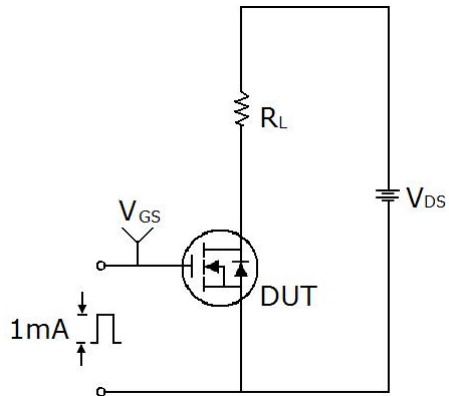


Figure9. Gate charge waveforms

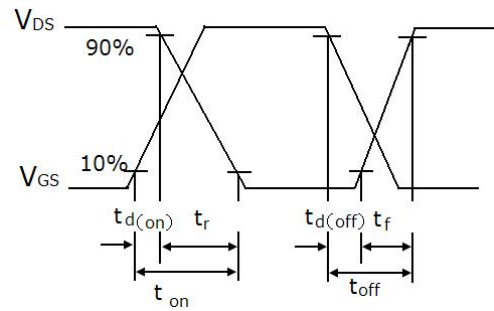
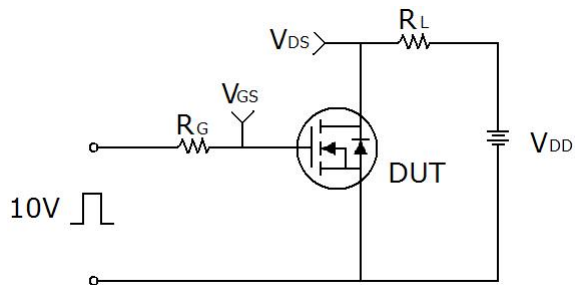


Test circuit

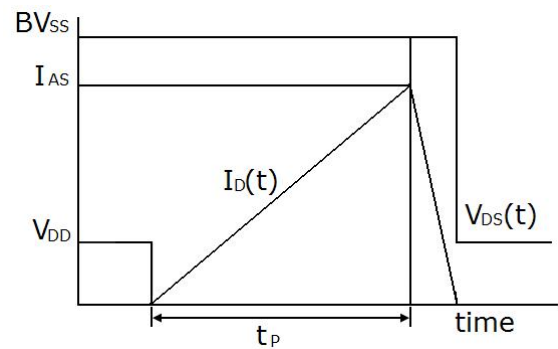
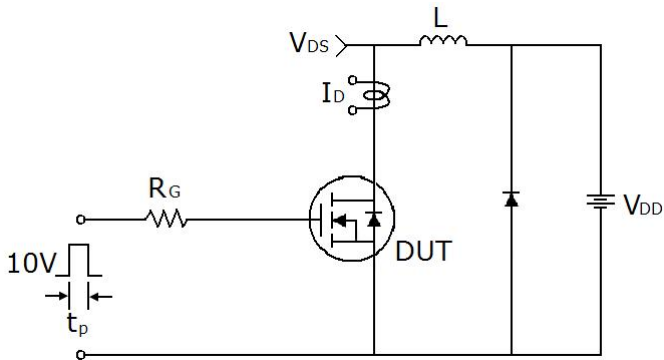
1) Gate charge test circuit & Waveform



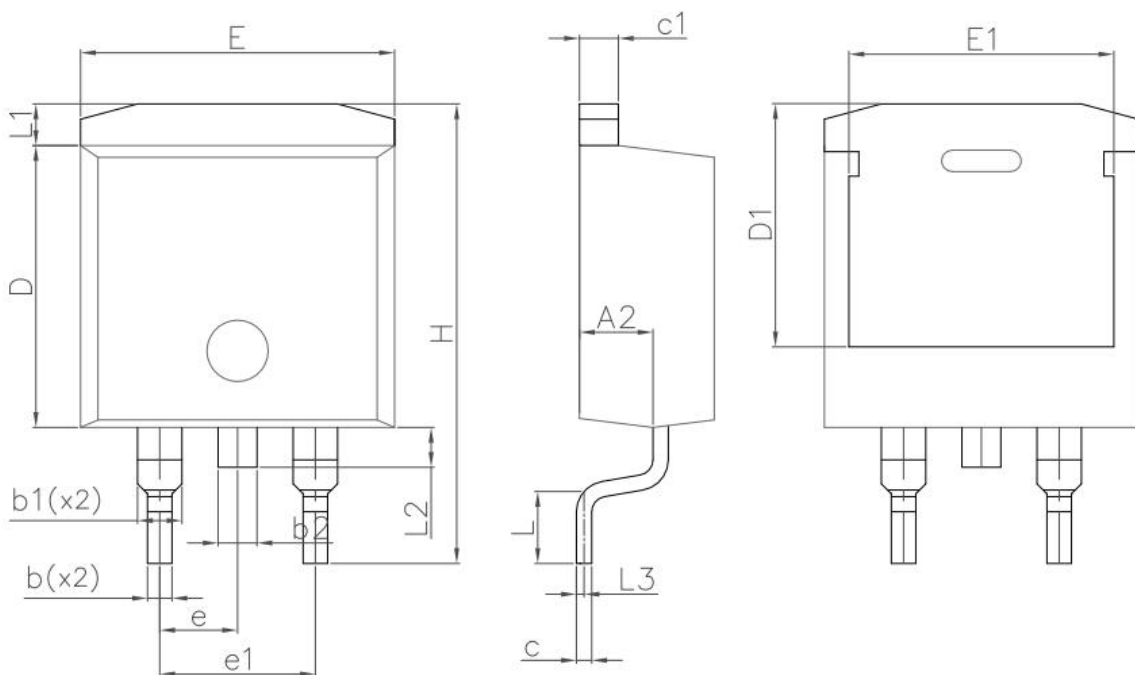
2) Switch Time Test Circuit:



3) Unclamped Inductive Switching Test Circuit & Waveforms



TO-263-E Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.20	4.60	0.165	0.181
A2	2.20	2.60	0.087	0.102
b	0.70	0.90	0.028	0.035
b1	1.20	1.75	0.047	0.069
b2	1.17	1.37	0.046	0.054
c	0.40	0.60	0.016	0.024
c1	1.15	1.40	0.045	0.055
D	9.10	9.30	0.358	0.366
D1	7.63	8.23	0.300	0.324
E	10.05	10.45	0.396	0.411
E1	8.35	8.95	0.329	0.352
e	2.54BSC		0.100BSC	
e1	5.08BSC		0.200BSC	
H	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	1.36REF		0.054REF	
L2	1.30REF		0.051REF	

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